

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/632,570	LIAW, JHON-JHY	
	<b>Examiner</b> Lan Vinh	<b>Art Unit</b> 1765	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner